

# IEC QUALITY ASSESSMENT SYSTEM FOR ELECTRONIC COMPONENTS (IECQ-CECC)

Annex A

## Description of Testing Facilities

Page 1 of 1

Issued in conjunction with certificate number: 5013867/07.11

Test Laboratory:

Intel Mobile Communications GmbH  
IMC QM RTC

TESTS according to DIN EN 190 000 and JEDEC

High Temperature Storage Life (HTSL)	Inspection for ext. package defects (EVI)
High Temperature Operating Life Test (HTOL)	Lid Torque (LT)
Low Temperature Operating Life Test (LTOL)	Latch-up Robustness (LU)
Non Flammability (NF)	Physical Dimensions (PD)
Temperature Cycling (TC)	Mechanical Lead Strength (LJ)
Mechanical Stress (MSQ)	Solderability (SD)
Power Temperature Cycling (PTC)	Preconditioning (PC)
Water Vapour Pressure Test/Pressure Cooker (AC)	X-ray (XI)
Temperature Humidity Bias or HAST (THB)	ESD Test (HBM, MM, CDM, SDM)
Corrosion Resistance of Metallic Parts (SM)	ESD System Level Test gun test (SLT)
Necessity for Dry Packing (DP)	Development of humidity/ live test boards
	"2nd Level Reliability (On Board)" Tests
	- Bend Test (BT)
	- Cyclic Bend Test (CBT)
	- TC on Board (TCoB)
	- Drop Test (DT)

**MC**  
Management  
Committee  
**CABC**  
Conformity Assessment Bodies  
Committee

NOTE: This certificate is valid only in conjunction with the approval document(s).

This approval and this certificate may be suspended or withdrawn in accordance with the Rules of CENELEC Electronic Components Committee (CECC).

This certificate remains the property of the body which granted it.

This approval is valid until 2014-11-15



VDE ASSOCIATION FOR ELECTRICAL,  
ELECTRONIC & INFORMATION TECHNOLOGIES  
VDE Prüf- und Zertifizierungsinstitut GmbH  
VDE Testing and Certification Institute  
IECQ Certification Body

63069 Offenbach/Germany  
Date: 2012-04-26  
VDE ref.: 5013867-9112-0001/16274#

# IEC QUALITY ASSESSMENT SYSTEM FOR ELECTRONIC COMPONENTS (IECQ-CECC)

## CERTIFICATE OF APPROVAL OF INDEPENDENT TEST LABORATORY IECQ 03-6

REGISTRATION NUMBER:

5013867/07.11

OF:

Intel Mobile Communications GmbH  
IMC QM RTC

AT THEIR PLACE OF WORK:

Am Campeon 10-12, 85579 Neubiberg, Germany

IN RESPECT OF GENERIC/SECTIONAL SPECIFICATION:

DIN EN 190 000

Monolith integrated circuits

For further details regarding the scope of testing facilities refer to Annex A

THE ORGANIZATION AND FACILITIES AT THE ABOVE PLACE OF WORK HAVE BEEN FOUND TO COMPLY WITH THE REQUIREMENTS OF DOCUMENTS  
IECQ 01, IECQ 03-6, DIN EN ISO/IEC 17025:2005 AND DIN EN ISO 9001:2008 FOR THE TESTING OF ELECTRONIC COMPONENTS.

THIS APPROVAL CERTIFICATE ALSO COVERS ALL  
REQUIREMENTS OF DIN EN ISO/IEC 17025:2005 AND DIN EN ISO 9001:2008

**MC**

Management  
Committee

**CABC**

Conformity Assessment Bodies  
Committee

NOTE: This certificate is valid only in conjunction with the approval document(s).

This approval and this certificate may be suspended or withdrawn in accordance with IECQ 03-6

This certificate remains the property of the body which granted it.

This approval is valid until 2014-11-15

VDE ASSOCIATION FOR ELECTRICAL,  
ELECTRONIC & INFORMATION TECHNOLOGIES  
VDE Prüf- und Zertifizierungsinstitut GmbH  
VDE Testing and Certification Institute  
IECQ Certification Body

63069 Offenbach/Germany

Date: 2012-04-26

VDE ref.: 5013867-9112-0001/162744

